Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/517,360	NAKANO ET AL.
Examiner	Art Unit

2833

Phuongchi Nguyen

	SEARCHED				
Class	Subclass	Date	Examiner		
439	417	2/27/2006	С		
439	499	2/27/2006	С		
439	404	2/27/2006	С		
439	405	2/27/2006	С		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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